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 15 SRS: (shielded adj probe) test54
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 15 L1: (66) ("3787762") or ("3953986") or ("6488223") or ("
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 15 S1: (3) (shielded adj probe) near5 test54 near1 (semicond
 15 S2: (58) probe with triaxial adj cable
 15 S3: (14350; 324/754-765,150.1.ccis.
 15 S4: (66) S2 and S3
 15 S5: (5) (shielded adj probe) near5 test54
 15 S6: (5) (shielded adj probe) near5 test54
 15 S7: (193) probe and triaxial adj cable
 15 S8: (14350; 324/754-765,150.1.ccis.
 15 S9: (86) S7 and S8
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 (shielded adj probe) and test54 near1 (semiconductor or integrated adj circuit)

Document ID	Issue Date	Pages	Title	Current On	Current IRef	Retrieval C	Inventor	S	C	E	W	U	D	M
US 20040174171 A1	200403209	15	Apparatus and method for terminating probe apparatus	324/754			Root, Bryan J. et al.	✓	✓	✓	✓	✓	✓	✓
US 20040080926 A1	200403161	11	Shielded probe apparatus for testing semiconductor wafer	324/754			Root, Bryan J. et al.	✓	✓	✓	✓	✓	✓	✓
US 20030221663 A1	20031204	15	Apparatus for providing controlled impedance in an	439/628			Johnson, David A. et al.	✓	✓	✓	✓	✓	✓	✓
US 20030375027 A1	20030620	53	Triaxial probe assembly	324/765			Holliman, Kenneth et al.	✓	✓	✓	✓	✓	✓	✓
US 20010000947 A1	20010510	34	Test socket	324/755			Swart, Mark A. et al.	✓	✓	✓	✓	✓	✓	✓
US 6727718 B1	20040427	12	Probe card and probe needle for high frequency testing	324/754	324/761		Shafiq, Adnan K.	✓	✓	✓	✓	✓	✓	✓
US 6700397 B2	20040302	49	Triaxial probe assembly	324/762	324/765		Holliman, Kenneth et al.	✓	✓	✓	✓	✓	✓	✓
US 6204280 B1	20010320	13	Test socket	324/761	324/755; 324/756		Swart, Mark A. et al.	✓	✓	✓	✓	✓	✓	✓
US 5967845 A	19991019	13	Apparatus for providing controlled impedance in an	439/620	439/66		Johnson, David A. et al.	✓	✓	✓	✓	✓	✓	✓

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